

Hierarchical identification of NBTI-critical gates in nanoscale logic

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Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

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Identifying NBTI-critical paths in nanoscale logic

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Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG

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SPICE-inspired fast gate-level computation of NBTI-induced delays in nanoscale logic

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